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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	300
Number of Logic Elements/Cells	3840
Total RAM Bits	221184
Number of I/O	102
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6slx4-3tqg144i

SelectIO™ Interface DC Input and Output Levels

Table 7: Recommended Operating Conditions for User I/Os Using Single-Ended Standards

I/O Standard	V _{CCO} for Drivers ⁽¹⁾			V _{REF} for Inputs		
	V, Min	V, Nom	V, Max	V, Min	V, Nom	V, Max
LVTTTL	3.0	3.3	3.45	V _{REF} is not used for these I/O standards		
LVC MOS33	3.0	3.3	3.45			
LVC MOS25	2.3	2.5	2.7			
LVC MOS18	1.65	1.8	1.95			
LVC MOS18_JEDEC	1.65	1.8	1.95			
LVC MOS15	1.4	1.5	1.6			
LVC MOS15_JEDEC	1.4	1.5	1.6			
LVC MOS12	1.1	1.2	1.3			
LVC MOS12_JEDEC	1.1	1.2	1.3			
PCI33_3 ⁽²⁾	3.0	3.3	3.45			
PCI66_3 ⁽²⁾	3.0	3.3	3.45			
I2C	2.7	3.0	3.45			
SMBUS	2.7	3.0	3.45			
SDIO	3.0	3.3	3.45			
MOBILE_DDR	1.7	1.8	1.9			
HSTL_I	1.4	1.5	1.6	0.68	0.75	0.9
HSTL_II	1.4	1.5	1.6	0.68	0.75	0.9
HSTL_III	1.4	1.5	1.6	–	0.9	–
HSTL_I_18	1.7	1.8	1.9	0.8	0.9	1.1
HSTL_II_18	1.7	1.8	1.9	–	0.9	–
HSTL_III_18	1.7	1.8	1.9	–	1.1	–
SSTL3_I	3.0	3.3	3.45	1.3	1.5	1.7
SSTL3_II	3.0	3.3	3.45	1.3	1.5	1.7
SSTL2_I	2.3	2.5	2.7	1.13	1.25	1.38
SSTL2_II	2.3	2.5	2.7	1.13	1.25	1.38
SSTL18_I	1.7	1.8	1.9	0.833	0.9	0.969
SSTL18_II	1.7	1.8	1.9	0.833	0.9	0.969
SSTL15_II	1.425	1.5	1.575	0.69	0.75	0.81

Notes:

1. V_{CCO} range required when using I/O standard for an output. Also required for MOBILE_DDR, PCI33_3, LVC MOS18_JEDEC, LVC MOS15_JEDEC, and LVC MOS12_JEDEC inputs, and for LVC MOS25 inputs when V_{CCAUX} = 3.3V.
2. For PCI systems, the transmitter and receiver should have common supplies for V_{CCO}.

Table 14: GTP Transceiver Current Supply (per Lane)

Symbol	Description	Typ ⁽¹⁾	Max	Units
I _{MGTAVCC}	GTP transceiver internal analog supply current	40.4	Note 2	mA
I _{MGTAVTTTX}	GTP transmitter termination supply current	27.4		mA
I _{MGTAVTTRX}	GTP receiver termination supply current	13.6		mA
I _{MGTAVCCPLL}	GTP transmitter and receiver PLL supply current	28.7		mA
R _{MGTRREF}	Precision reference resistor for internal calibration termination	50.0 ± 1% tolerance		Ω

Notes:

- Typical values are specified at nominal voltage, 25°C, with a 2.5 Gb/s line rate, with a shared PLL use mode.
- Values for currents of other transceiver configurations and conditions can be obtained by using the XPOWER Estimator (XPE) or XPOWER Analyzer (XPA) tools.

Table 15: GTP Transceiver Quiescent Supply Current (per Lane)⁽¹⁾⁽²⁾⁽³⁾⁽⁴⁾

Symbol	Description	Typ ⁽⁵⁾	Max	Units
I _{MGTAVCCQ}	Quiescent MGTAVCC supply current	1.7	Note 2	mA
I _{MGTAVTTTXQ}	Quiescent MGTAVTTTX supply current	0.1		mA
I _{MGTAVTTRXQ}	Quiescent MGTAVTTRX supply current	1.2		mA
I _{MGTAVCCPLLQ}	Quiescent MGTAVCCPLL supply current	1.0		mA

Notes:

- Device powered and unconfigured.
- Currents for conditions other than values specified in this table can be obtained by using the XPOWER Estimator (XPE) or XPOWER Analyzer (XPA) tools.
- GTP transceiver quiescent supply current for an entire device can be calculated by multiplying the values in this table by the number of available GTP transceivers.
- Does not include power-up MGTAVTTRCAL supply current during device configuration.
- Typical values are specified at nominal voltage, 25°C.

Switching Characteristics

All values represented in this data sheet are based on these speed specifications: v1.20 for -3, -3N, and -2; and v1.08 for -1L. Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Production

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

All specifications are always representative of worst-case supply voltage and junction temperature conditions.

Since individual family members are produced at different times, the migration from one category to another depends completely on the status of the fabrication process for each device.

The -1L speed grade refers to the lower-power Spartan-6 devices. The -3N speed grade refers to the Spartan-6 devices that do not support MCB functionality.

[Table 26](#) correlates the current status of each Spartan-6 device on a per speed grade basis.

Testing of Switching Characteristics

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Spartan-6 devices.

Table 26: Spartan-6 Device Speed Grade Designations

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XC6SLX4 ⁽¹⁾			-3, -2, -1L
XC6SLX9			-3, -3N, -2, -1L
XC6SLX16			-3, -3N, -2, -1L
XC6SLX25			-3, -3N, -2, -1L
XC6SLX25T			-3, -3N, -2
XC6SLX45			-3, -3N, -2, -1L
XC6SLX45T			-3, -3N, -2
XC6SLX75			-3, -3N, -2, -1L
XC6SLX75T			-3, -3N, -2
XC6SLX100			-3, -3N, -2, -1L
XC6SLX100T			-3, -3N, -2
XC6SLX150			-3, -3N, -2, -1L
XC6SLX150T			-3, -3N, -2
XA6SLX4			-3, -2
XA6SLX9			-3, -2
XA6SLX16			-3, -2
XA6SLX25			-3, -2
XA6SLX25T			-3, -2
XA6SLX45			-3, -2
XA6SLX45T			-3, -2
XA6SLX75			-3, -2
XA6SLX75T			-3, -2
XA6SLX100			-2
XQ6SLX75			-2, -1L
XQ6SLX75T			-3, -2
XQ6SLX150			-2, -1L
XQ6SLX150T			-3, -2

Notes:

1. The XC6SLX4 is not available in the -3N speed grade.

Table 27: Spartan-6 Device Production Software and Speed Specification Release⁽¹⁾ (Cont'd)

Device	Speed Grade Designations ⁽²⁾			
	-3 ⁽³⁾	-3N	-2 ⁽⁴⁾	-1L
XQ6SLX75	N/A	N/A	ISE 13.2 v1.19	ISE 13.2 v1.07
XQ6SLX75T	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XQ6SLX150	N/A	N/A	ISE 13.2 v1.19	ISE 13.2 v1.07
XQ6SLX150T	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A

Notes:

1. ISE 13.3 software with v1.20 for -3, -3N, and -2; and v1.08 for -1L speed specification reflects the changes outlined in [XCEN11028: Spartan-6 FPGA Speed File Changes](#).
2. As marked with an N/A, LXT devices and all XA devices are not available with a -1L speed grade; LX4 devices and all XA and XQ devices are not available with a -3N speed grade.
3. Improved -3 specifications reflected in this data sheet require ISE 12.4 software with v1.15 speed specification.
4. Improved -2 specifications reflected in this data sheet require ISE 12.4 software and the *12.4 Speed Files Patch* which contains the v1.17 speed specification available on the [Xilinx Download Center](#).
5. ISE 12.3 software with v1.12 speed specification is available using ISE 12.3 software and the *12.3 Speed Files Patch* available on the [Xilinx Download Center](#).
6. ISE 12.2 software with v1.11 speed specification is available using ISE 12.2 software and the *12.2 Speed Files Patch* available on the [Xilinx Download Center](#).
7. ISE 13.1 software with v1.18 speed specification is available using ISE 13.1 software and the *13.1 Update* available on the [Xilinx Download Center](#). See [XCEN11012: Speed File Change for -3N Devices](#).

IOB Pad Input/Output/3-State Switching Characteristics

[Table 28](#) (for commercial (XC) Spartan-6 devices) and [Table 29](#) (for Automotive XA Spartan-6 and Defense-grade Spartan-6Q devices) summarizes the values of standard-specific data input delays, output delays terminating at pads (based on standard), and 3-state delays.

- T_{IOPI} is described as the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.
- T_{IOOP} is described as the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.
- T_{IOTP} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer.

See the TRACE report for further information on delays when using an I/O standard with UNTUNED termination on inputs or outputs.

Table 28: IOB Switching Characteristics for the Commercial (XC) Spartan-6 Devices

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	
LVDS_33	1.17	1.29	1.42	1.68	1.55	1.69	1.89	2.42	3000	3000	3000	3000	ns
LVDS_25	1.01	1.13	1.26	1.57	1.65	1.79	1.99	2.47	3000	3000	3000	3000	ns
BLVDS_25	1.02	1.14	1.27	1.57	1.72	1.86	2.06	2.68	1.72	1.86	2.06	2.68	ns
MINI_LVDS_33	1.17	1.29	1.42	1.68	1.57	1.71	1.91	2.41	3000	3000	3000	3000	ns
MINI_LVDS_25	1.01	1.13	1.26	1.57	1.65	1.79	1.99	2.47	3000	3000	3000	3000	ns
LVPECL_33	1.18	1.30	1.43	1.68	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	ns
LVPECL_25	1.02	1.14	1.27	1.57	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	ns
RSDS_33 (point to point)	1.17	1.29	1.42	1.68	1.57	1.71	1.91	2.42	3000	3000	3000	3000	ns
RSDS_25 (point to point)	1.01	1.13	1.26	1.56	1.65	1.79	1.99	2.47	3000	3000	3000	3000	ns
TMDS_33	1.21	1.33	1.46	1.71	1.54	1.68	1.88	2.50	3000	3000	3000	3000	ns

Table 29: IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices⁽¹⁾ (Cont'd)

I/O Standard	T _{IOPI}		T _{IOOP}		T _{IOTP}		Units
	Speed Grade		Speed Grade		Speed Grade		
	-3	-2	-3	-2	-3	-2	
DIFF_SSTL3_I	1.26	1.44	1.95	2.15	1.95	2.15	ns
DIFF_SSTL3_II	1.26	1.44	1.94	2.14	1.94	2.14	ns
DIFF_SSTL2_I	1.09	1.27	1.94	2.14	1.94	2.14	ns
DIFF_SSTL2_II	1.09	1.27	1.90	2.10	1.90	2.10	ns
DIFF_SSTL18_I	1.04	1.22	1.86	2.06	1.86	2.06	ns
DIFF_SSTL18_II	1.05	1.23	1.82	2.02	1.82	2.02	ns
DIFF_SSTL15_II	1.01	1.19	1.81	2.01	1.81	2.01	ns
DIFF_MOBILE_DDR	1.04	1.22	1.89	2.09	1.89	2.09	ns
LVTTL, QUIETIO, 2 mA	1.42	1.60	5.64	5.84	5.64	5.84	ns
LVTTL, QUIETIO, 4 mA	1.42	1.60	4.46	4.66	4.46	4.66	ns
LVTTL, QUIETIO, 6 mA	1.42	1.60	3.92	4.12	3.92	4.12	ns
LVTTL, QUIETIO, 8 mA	1.42	1.60	3.37	3.57	3.37	3.57	ns
LVTTL, QUIETIO, 12 mA	1.42	1.60	3.42	3.62	3.42	3.62	ns
LVTTL, QUIETIO, 16 mA	1.42	1.60	3.09	3.29	3.09	3.29	ns
LVTTL, QUIETIO, 24 mA	1.42	1.60	2.83	3.03	2.83	3.03	ns
LVTTL, Slow, 2 mA	1.42	1.60	4.58	4.78	4.58	4.78	ns
LVTTL, Slow, 4 mA	1.42	1.60	3.38	3.58	3.38	3.58	ns
LVTTL, Slow, 6 mA	1.42	1.60	2.95	3.15	2.95	3.15	ns
LVTTL, Slow, 8 mA	1.42	1.60	2.73	2.93	2.73	2.93	ns
LVTTL, Slow, 12 mA	1.42	1.60	2.72	2.92	2.72	2.92	ns
LVTTL, Slow, 16 mA	1.42	1.60	2.53	2.73	2.53	2.73	ns
LVTTL, Slow, 24 mA	1.42	1.60	2.42	2.62	2.42	2.62	ns
LVTTL, Fast, 2 mA	1.42	1.60	4.04	4.24	4.04	4.24	ns
LVTTL, Fast, 4 mA	1.42	1.60	2.66	2.86	2.66	2.86	ns
LVTTL, Fast, 6 mA	1.42	1.60	2.58	2.78	2.58	2.78	ns
LVTTL, Fast, 8 mA	1.42	1.60	2.46	2.66	2.46	2.66	ns
LVTTL, Fast, 12 mA	1.42	1.60	1.97	2.17	1.97	2.17	ns
LVTTL, Fast, 16 mA	1.42	1.60	1.97	2.17	1.97	2.17	ns
LVTTL, Fast, 24 mA	1.42	1.60	1.97	2.17	1.97	2.17	ns
LVC MOS33, QUIETIO, 2 mA	1.41	1.59	5.65	5.85	5.65	5.85	ns
LVC MOS33, QUIETIO, 4 mA	1.41	1.59	4.20	4.40	4.20	4.40	ns
LVC MOS33, QUIETIO, 6 mA	1.41	1.59	3.65	3.85	3.65	3.85	ns
LVC MOS33, QUIETIO, 8 mA	1.41	1.59	3.51	3.71	3.51	3.71	ns
LVC MOS33, QUIETIO, 12 mA	1.41	1.59	3.09	3.29	3.09	3.29	ns
LVC MOS33, QUIETIO, 16 mA	1.41	1.59	2.91	3.11	2.91	3.11	ns
LVC MOS33, QUIETIO, 24 mA	1.41	1.59	2.73	2.93	2.73	2.93	ns
LVC MOS33, Slow, 2 mA	1.41	1.59	4.59	4.79	4.59	4.79	ns
LVC MOS33, Slow, 4 mA	1.41	1.59	3.14	3.34	3.14	3.34	ns

Output Delay Measurements

Output delays are measured using a Tektronix P6245 TDS500/600 probe (< 1 pF) across approximately 4" of FR4 microstrip trace. Standard termination was used for all testing. The propagation delay of the 4" trace is characterized separately and subtracted from the final measurement, and is therefore not included in the generalized test setups shown in Figure 4 and Figure 5.

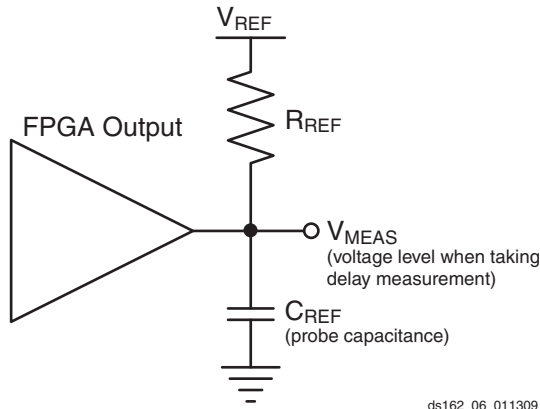
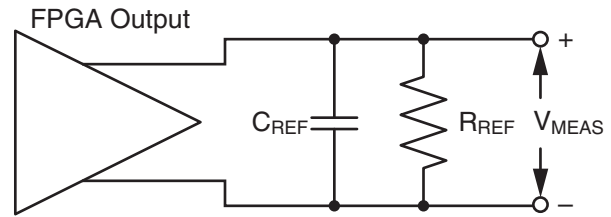


Figure 4: Single-Ended Test Setup



ds162_07_011309

Figure 5: Differential Test Setup

Measurements and test conditions are reflected in the IBIS models except where the IBIS format precludes it. Parameters V_{REF} , R_{REF} , C_{REF} , and V_{MEAS} fully describe the test conditions for each I/O standard. The most accurate prediction of propagation delay in any given application can be obtained through IBIS simulation, using the following method:

1. Simulate the output driver of choice into the generalized test setup, using values from Table 32.
2. Record the time to V_{MEAS} .
3. Simulate the output driver of choice into the actual PCB trace and load, using the appropriate IBIS model or capacitance value to represent the load.
4. Record the time to V_{MEAS} .
5. Compare the results of steps 2 and 4. The increase or decrease in delay yields the actual propagation delay of the PCB trace.

Table 32: Output Delay Measurement Methodology

Description	I/O Standard Attribute	R_{REF} (Ω)	$C_{REF}^{(1)}$ (pF)	V_{MEAS} (V)	V_{REF} (V)
LVTTTL (Low-Voltage Transistor-Transistor Logic)	LVTTTL (all)	1M	0	1.4	0
LVC MOS (Low-Voltage CMOS), 3.3V	LVC MOS33	1M	0	1.65	0
LVC MOS, 2.5V	LVC MOS25	1M	0	1.25	0
LVC MOS, 1.8V	LVC MOS18	1M	0	0.9	0
LVC MOS, 1.5V	LVC MOS15	1M	0	0.75	0
LVC MOS, 1.2V	LVC MOS12	1M	0	0.6	0
PCI (Peripheral Component Interface) 33 MHz and 66 MHz, 3.3V	PCI33_3, PCI66_3 (rising edge)	25	10 ⁽²⁾	0.94	0
	PCI33_3, PCI66_3 (falling edge)	25	10 ⁽²⁾	2.03	3.3
HSTL (High-Speed Transceiver Logic), Class I	HSTL_I	50	0	V_{REF}	0.75
HSTL, Class II	HSTL_II	25	0	V_{REF}	0.75
HSTL, Class III	HSTL_III	50	0	0.9	1.5
HSTL, Class I, 1.8V	HSTL_I_18	50	0	V_{REF}	0.9
HSTL, Class II, 1.8V	HSTL_II_18	25	0	V_{REF}	0.9
HSTL, Class III, 1.8V	HSTL_III_18	50	0	1.1	1.8
SSTL (Stub Series Terminated Logic), Class I, 1.8V	SSTL18_I	50	0	V_{REF}	0.9
SSTL, Class II, 1.8V	SSTL18_II	25	0	V_{REF}	0.9
SSTL, Class I, 2.5V	SSTL2_I	50	0	V_{REF}	1.25

Table 34: SSO Limit per V_{CCO}/GND Pair (Cont'd)

V_{CCO}	I/O Standard	Drive	Slew	SSO Limit per V_{CCO}/GND Pair			
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324	
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5
Various	LVDS_33			16	N/A	16	N/A
	LVDS_25			20	N/A	20	N/A
	BLVDS_25			20	48	20	20
	MINI_LVDS_33			13	N/A	13	N/A
	MINI_LVDS_25			18	N/A	18	N/A
	RSDS_33			12	N/A	12	N/A
	RSDS_25			15	N/A	15	N/A
	TMDS_33			83	N/A	83	N/A
	PPDS_33			12	N/A	12	N/A
	PPDS_25			16	N/A	16	N/A
	DISPLAY_PORT			42	40	42	30
	I2C			47	55	47	42
	SMBUS			44	52	44	40

Notes:

- SSO limits greater than the number of I/O per V_{CCO}/GND pair (Table 33) indicate No Limit for the given I/O standard. They are provided in this table to calculate limits when using multiple I/O standards in a bank.
- Not available (N/A) indicates that the I/O standard is not available in the given bank.
- When used with the MCB, these signals are exempt from SSO analysis due to the known activity of the MCB switching patterns. SSO performance is validated for all MCB instances. MCB outputs can, in some cases, exceed the SSO limits.

Table 45: Device DNA Interface Port Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
T _{DNASSU}	Setup time on SHIFT before the rising edge of CLK	7				ns, Min
T _{DNASH}	Hold time on SHIFT after the rising edge of CLK	1				ns, Min
T _{DNADSU}	Setup time on DIN before the rising edge of CLK	7				ns, Min
T _{DNADH}	Hold time on DIN after the rising edge of CLK	1				ns, Min
T _{DNARSU}	Setup time on READ before the rising edge of CLK	7				ns, Min
		1,000				ns, Max
T _{DNARH}	Hold time on READ after the rising edge of CLK	1				ns, Min
T _{DNADCKO}	Clock-to-output delay on DOUT after rising edge of CLK	0.5				ns, Min
		6				ns, Max
T _{DNACKF} ⁽²⁾	CLK frequency	2				MHz, Max
T _{DNACKL}	CLK Low time	50				ns, Min
T _{DNACKH}	CLK High time	50				ns, Min

Notes:

1. The minimum READ pulse width is 8 ns, the maximum READ pulse width is 1 μ s.
2. Also applies to TCK when reading DNA through the boundary-scan port.

Table 46: Suspend Mode Switching Characteristics

Symbol	Description	Min	Max	Units
Entering Suspend Mode				
T _{SUSPENDHIGH_AWAKE}	Rising edge of SUSPEND pin to falling edge of AWAKE pin without glitch filter	2.5	14	ns
T _{SUSPENDFILTER}	Adjustment to SUSPEND pin rising edge parameters when glitch filter enabled	31	430	ns
T _{SUSPEND_GWE}	Rising edge of SUSPEND pin until FPGA output pins drive their defined SUSPEND constraint behavior (without glitch filter)	–	15	ns
T _{SUSPEND_GTS}	Rising edge of SUSPEND pin to write-protect lock on all writable clocked elements (without glitch filter)	–	15	ns
T _{SUSPEND_DISABLE}	Rising edge of the SUSPEND pin to FPGA input pins and interconnect disabled (without glitch filter)	–	1500	ns
Exiting Suspend Mode				
T _{SUSPENDLOW_AWAKE}	Falling edge of the SUSPEND pin to rising edge of the AWAKE pin. Does not include DCM or PLL lock time.	7	75	μ s
T _{SUSPEND_ENABLE}	Falling edge of the SUSPEND pin to FPGA input pins and interconnect re-enabled	7	41	μ s
T _{AWAKE_GWE1}	Rising edge of the AWAKE pin until write-protect lock released on all writable clocked elements, using sw_clk:InternalClock and sw_gwe_cycle:1 .	–	80	ns
T _{AWAKE_GWE512}	Rising edge of the AWAKE pin until write-protect lock released on all writable clocked elements, using sw_clk:InternalClock and sw_gwe_cycle:512 .	–	20.5	μ s
T _{AWAKE_GTS1}	Rising edge of the AWAKE pin until outputs return to the behavior described in the FPGA application, using sw_clk:InternalClock and sw_gts_cycle:1 .	–	80	ns
T _{AWAKE_GTS512}	Rising edge of the AWAKE pin until outputs return to the behavior described in the FPGA application, using sw_clk:InternalClock and sw_gts_cycle:512 .	–	20.5	μ s
T _{SCP_AWAKE}	Rising edge of SCP pins to rising edge of AWAKE pin	7	75	μ s

Clock Buffers and Networks

Table 48: Global Clock Switching Characteristics (BUFGMUX)

Symbol	Description	Devices	Speed Grade				Units
			-3	-3N	-2	-1L	
T _{GSI}	S pin Setup to I0/I1 inputs	LX devices	0.25	0.31	0.48	0.48	ns
		LXT devices	0.25	0.31	0.48	N/A	ns
T _{GIO}	BUFGMUX delay from I0/I1 to O	LX devices	0.21	0.21	0.21	0.21	ns
		LXT devices	0.21	0.21	0.21	N/A	ns
Maximum Frequency							
F _{MAX}	Global clock tree (BUFGMUX)	LX devices	400	400	375	250	MHz
		LXT devices	400	400	375	N/A	MHz

Table 49: Input/Output Clock Switching Characteristics (BUFIO2)

Symbol	Description	Devices	Speed Grade				Units
			-3	-3N	-2	-1L	
T _{BUFCO_O}	Clock to out delay from I to O	LX devices	0.67	0.82	1.09	1.50	ns
		LXT devices	0.67	0.82	1.09	N/A	ns
Maximum Frequency							
F _{MAX}	I/O clock tree (BUFIO2)	LX devices	540	525	500	300	MHz
		LXT devices	540	525	500	N/A	MHz

Table 50: Input/Output Clock Switching Characteristics (BUFIO2FB)

Symbol	Description	Devices	Speed Grade				Units
			-3	-3N	-2	-1L	
Maximum Frequency							
F _{MAX}	I/O clock tree (BUFIO2FB)	LX devices	1080	1050	950	500	MHz
		LXT devices	1080	1050	950	N/A	MHz

Table 51: Input/Output Clock Switching Characteristics (BUFPLL)

Symbol	Description	Devices	Speed Grade				Units
			-3	-3N	-2	-1L	
Maximum Frequency							
F _{MAX}	BUFPLL clock tree (BUFPLL)	LX devices	1080	1050	950	500	MHz
		LXT devices	1080	1050	950	N/A	MHz

PLL Switching Characteristics

Table 52: PLL Specification

Symbol	Description	Device ⁽¹⁾	Speed Grade				Units
			-3	-3N	-2	-1L	
F_{INMAX}	Maximum Input Clock Frequency from I/O Clock	LX devices	540	525	450	300	MHz
		LXT devices	540	525	450	N/A	MHz
	Maximum Input Clock Frequency from Global Clock	LX devices	400	400	375	250	MHz
		LXT devices	400	400	375	N/A	MHz

Table 54: Switching Characteristics for the Delay-Locked Loop (DLL)⁽¹⁾

Symbol	Description	Speed Grade								Units
		-3		-3N		-2		-1L		
		Min	Max	Min	Max	Min	Max	Min	Max	
Output Frequency Ranges										
CLKOUT_FREQ_CLK0	Frequency for the CLK0 and CLK180 outputs.	5	280	5	280	5	250	5	175	MHz
CLKOUT_FREQ_CLK90	Frequency for the CLK90 and CLK270 outputs.	5	200	5	200	5	200	5	175	MHz
CLKOUT_FREQ_2X	Frequency for the CLK2X and CLK2X180 outputs.	10	375	10	375	10	334	10	250	MHz
CLKOUT_FREQ_DV	Frequency for the CLKDV output.	0.3125	186	0.3125	186	0.3125	166	0.3125	88.6	MHz
Output Clock Jitter ⁽²⁾⁽³⁾⁽⁴⁾										
CLKOUT_PER_JITT_0	Period jitter at the CLK0 output.	–	±100	–	±100	–	±100	–	±100	ps
CLKOUT_PER_JITT_90	Period jitter at the CLK90 output.	–	±150	–	±150	–	±150	–	±150	ps
CLKOUT_PER_JITT_180	Period jitter at the CLK180 output.	–	±150	–	±150	–	±150	–	±150	ps
CLKOUT_PER_JITT_270	Period jitter at the CLK270 output.	–	±150	–	±150	–	±150	–	±150	ps
CLKOUT_PER_JITT_2X	Period jitter at the CLK2X and CLK2X180 outputs.	Maximum = ±[0.5% of CLKIN period + 100]								ps
CLKOUT_PER_JITT_DV1	Period jitter at the CLKDV output when performing integer division.	–	±150	–	±150	–	±150	–	±150	ps
CLKOUT_PER_JITT_DV2	Period jitter at the CLKDV output when performing non-integer division.	Maximum = ±[0.5% of CLKIN period + 100]								ps
Duty Cycle ⁽⁴⁾										
CLKOUT_DUTY_CYCLE_DLL	Duty cycle variation for the CLK0, CLK90, CLK180, CLK270, CLK2X, CLK2X180, and CLKDV outputs, including the BUFGMUX and clock tree duty-cycle distortion.	Typical = ±[1% of CLKIN period + 350]								ps
Phase Alignment ⁽⁴⁾										
CLKIN_CLKFB_PHASE	Phase offset between the CLKIN and CLKFB inputs (CLK_FEEDBACK = 1X).	–	±150	–	±150	–	±150	–	±250	ps
	Phase offset between the CLKIN and CLKFB inputs (CLK_FEEDBACK = 2X). ⁽⁶⁾	–	±250	–	±250	–	±250	–	±350	
CLKOUT_PHASE_DLL	Phase offset between DLL outputs for CLK0 to CLK2X (not CLK2X180).	Maximum = ±[1% of CLKIN period + 100]								ps
	Phase offset between DLL outputs for all others.	Maximum = ±[1% of CLKIN period + 150]						Maximum = ±[1% of CLKIN period + 200]		ps

Table 57: Switching Characteristics for the Digital Frequency Synthesizer DFS (DCM_CLKGEN)⁽¹⁾ (Cont'd)

Symbol	Description	Speed Grade								Units
		-3		-3N		-2		-1L		
		Min	Max	Min	Max	Min	Max	Min	Max	
Spread Spectrum										
F _{CLKIN_FIXED_SPREAD_SPECTRUM}	Frequency of the CLKIN input for fixed spread spectrum (SPREAD_SPECTRUM = CENTER_LOW_SPREAD/ CENTER_HIGH_SPREAD)	30	200	30	200	30	200	30	200	MHz
T _{CENTER_LOW_SPREAD} ⁽⁶⁾	Spread at the CLKFX output for fixed spread spectrum (SPREAD_SPECTRUM = CENTER_LOW_SPREAD)	Typical = $\frac{100}{\text{CLKFX_DIVIDE}}$ Maximum = 250								ps
T _{CENTER_HIGH_SPREAD} ⁽⁶⁾	Spread at the CLKFX output for fixed spread spectrum (SPREAD_SPECTRUM= CENTER_HIGH_SPREAD)	Typical = $\frac{240}{\text{CLKFX_DIVIDE}}$ Maximum = 400								ps
F _{MOD_FIXED_SPREAD_SPECTRUM} ⁽⁶⁾	Average modulation frequency when using fixed spread spectrum (SPREAD_SPECTRUM = CENTER_LOW_SPREAD / CENTER_HIGH_SPREAD)	Typical = F _{IN} /1024								MHz

Notes:

- The values in this table are based on the operating conditions described in Table 2 and Table 55.
- For optimal jitter tolerance and a faster LOCK time, use the CLKIN_PERIOD attribute.
- Output jitter is characterized with no input jitter. Output jitter strongly depends on the environment, including the number of SSOs, the output drive strength, CLB utilization, CLB switching activities, switching frequency, power supply, and PCB design. The actual maximum output jitter depends on the system application.
- The CLKFX, CLKFXDV, and CLKFX180 outputs have a duty cycle of approximately 50%.
- Some duty-cycle and alignment specifications include a percentage of the CLKFX output period. For example, this data sheet specifies a maximum CLKFX jitter of $\pm(1\% \text{ of CLKFX period} + 200 \text{ ps})$. Assuming that the CLKFX output frequency is 100 MHz, the equivalent CLKFX period is 10 ns, and 1% of 10 ns is 0.1 ns or 100 ps. Accordingly, the maximum jitter is $\pm(100 \text{ ps} + 200 \text{ ps}) = \pm300 \text{ ps}$.
- When using CENTER_LOW_SPREAD, CENTER_HIGH_SPREAD, the valid values for CLKFX_MULTIPLY are limited to 2 through 32, and the valid values for CLKFX_DIVIDE are limited to 1 through 4.

Table 58: Recommended Operating Conditions for the Phase-Shift Clock in Variable Phase Mode (DCM_SP) or Dynamic Frequency Synthesis (DCM_CLKGEN)

Symbol	Description	Speed Grade								Units
		-3		-3N		-2		-1L		
		Min	Max	Min	Max	Min	Max	Min	Max	
Operating Frequency Ranges										
PSCLK_FREQ	Frequency for the PSCLK (DCM_SP) or PROGCLK (DCM_CLKGEN) input.	1	167	1	167	1	167	1	100	MHz
Input Pulse Requirements										
PSCLK_PULSE	PSCLK (DCM_SP) or PROGCLK (DCM_CLKGEN) pulse width as a percentage of the clock period.	40	60	40	60	40	60	40	60	%

Table 71: Global Clock Setup and Hold Without DCM or PLL (Default Delay)

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard. ⁽¹⁾							
T _{PSFD} / T _{PHFD}	Default Delay ⁽²⁾ Global Clock and IFF ⁽³⁾ without DCM or PLL	XC6SLX4	0.66/1.17	N/A	1.05/0.79	2.09/1.05	ns
		XC6SLX9	0.66/1.17	0.75/1.17	1.05/1.17	2.09/1.05	ns
		XC6SLX16	0.87/1.16	0.93/1.16	0.96/1.16	1.86/1.06	ns
		XC6SLX25	0.68/0.77	0.81/0.81	0.87/0.82	2.21/1.33	ns
		XC6SLX25T	0.68/0.77	0.81/0.81	0.87/0.82	N/A	ns
		XC6SLX45	0.40/1.05	0.42/1.17	0.64/1.20	1.61/1.67	ns
		XC6SLX45T	0.40/1.05	0.42/1.17	0.64/1.20	N/A	ns
		XC6SLX75	0.41/1.11	0.41/1.13	0.80/1.14	1.23/1.82	ns
		XC6SLX75T	0.41/1.11	0.41/1.13	0.80/1.14	N/A	ns
		XC6SLX100	0.39/1.12	0.39/1.23	0.39/1.28	1.13/1.94	ns
		XC6SLX100T	0.39/1.12	0.39/1.23	0.39/1.28	N/A	ns
		XC6SLX150	0.23/1.54	0.23/1.62	0.23/1.62	1.14/2.05	ns
		XC6SLX150T	0.23/1.54	0.23/1.62	0.23/1.62	N/A	ns
		XA6SLX4	0.73/1.18	N/A	1.05/0.80	N/A	ns
		XA6SLX9	0.73/1.18	N/A	1.05/0.80	N/A	ns
		XA6SLX16	0.90/1.20	N/A	0.96/0.75	N/A	ns
		XA6SLX25	0.70/0.81	N/A	0.87/0.91	N/A	ns
		XA6SLX25T	0.76/0.81	N/A	1.03/0.91	N/A	ns
		XA6SLX45	0.40/1.06	N/A	0.64/1.20	N/A	ns
		XA6SLX45T	0.40/1.06	N/A	0.64/1.20	N/A	ns
		XA6SLX75	0.41/1.24	N/A	0.80/1.18	N/A	ns
		XA6SLX75T	0.41/1.24	N/A	0.80/1.18	N/A	ns
		XA6SLX100	N/A	N/A	0.86/1.55	N/A	ns
		XQ6SLX75	N/A	N/A	0.80/1.18	1.23/1.82	ns
		XQ6SLX75T	0.41/1.24	N/A	0.80/1.18	N/A	ns
		XQ6SLX150	N/A	N/A	0.28/1.57	1.14/2.05	ns
		XQ6SLX150T	0.28/1.78	N/A	0.28/1.57	N/A	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
- Default delay uses IODELAY2 tap 0.
- IFF = Input Flip-Flop or Latch.

Table 75: Global Clock Setup and Hold With PLL in Source-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVC MOS25 Standard.(1)							
T _{PSPLL0} / T _{PHPLL0}	No Delay Global Clock and IFF(2) with PLL in Source-Synchronous Mode	XC6SLX4	0.47/1.08	N/A	0.47/1.60	1.15/1.68	ns
		XC6SLX9	0.47/1.08	0.47/1.35	0.47/1.60	1.15/1.68	ns
		XC6SLX16	0.37/0.75	0.37/0.82	0.51/0.94	0.57/1.31	ns
		XC6SLX25	0.69/1.06	0.69/1.06	0.69/1.06	1.86/1.67	ns
		XC6SLX25T	0.69/1.06	0.69/1.06	0.69/1.06	N/A	ns
		XC6SLX45	0.57/1.05	0.65/1.10	0.65/1.18	1.02/1.65	ns
		XC6SLX45T	0.57/1.06	0.65/1.10	0.65/1.18	N/A	ns
		XC6SLX75	0.86/1.04	0.87/1.04	0.90/1.04	1.34/1.55	ns
		XC6SLX75T	0.86/1.04	0.87/1.04	0.90/1.04	N/A	ns
		XC6SLX100	0.53/1.13	0.54/1.13	0.55/1.13	0.89/2.39	ns
		XC6SLX100T	0.53/1.13	0.54/1.13	0.55/1.13	N/A	ns
		XC6SLX150	0.50/1.31	0.51/1.31	0.52/1.31	1.02/1.72	ns
		XC6SLX150T	0.50/1.31	0.51/1.31	0.52/1.31	N/A	ns
		XA6SLX4	0.71/0.93	N/A	0.62/1.47	N/A	ns
		XA6SLX9	0.71/0.93	N/A	0.62/1.47	N/A	ns
		XA6SLX16	0.92/0.69	N/A	0.63/0.82	N/A	ns
		XA6SLX25	0.99/0.94	N/A	0.96/0.94	N/A	ns
		XA6SLX25T	0.99/0.94	N/A	1.04/0.94	N/A	ns
		XA6SLX45	0.63/1.02	N/A	0.72/1.05	N/A	ns
		XA6SLX45T	0.63/1.02	N/A	0.72/1.05	N/A	ns
		XA6SLX75	0.88/0.89	N/A	1.02/0.89	N/A	ns
		XA6SLX75T	0.88/0.89	N/A	1.02/0.89	N/A	ns
		XA6SLX100	N/A	N/A	1.25/0.96	N/A	ns
		XQ6SLX75	N/A	N/A	1.02/0.89	1.34/1.55	ns
		XQ6SLX75T	0.88/0.89	N/A	1.02/0.89	N/A	ns
		XQ6SLX150	N/A	N/A	0.63/1.19	1.02/1.72	ns
		XQ6SLX150T	0.60/1.19	N/A	0.63/1.19	N/A	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include PLL CLKOUT0 jitter.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 76: Global Clock Setup and Hold With DCM and PLL in System-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard. ⁽¹⁾							
T _{PSDCMPLL} / T _{PHDCMPLL}	No Delay Global Clock and IFF ⁽²⁾ with DCM in System-Synchronous Mode and PLL in DCM2PLL Mode.	XC6SLX4	1.16/0.49	N/A	1.39/0.49	2.36/0.59	ns
		XC6SLX9	1.16/0.44	1.37/0.44	1.39/0.44	2.36/0.59	ns
		XC6SLX16	1.44/−0.08	1.49/−0.04	1.62/−0.04	2.06/0.55	ns
		XC6SLX25	1.52/0.42	1.65/0.42	1.83/0.42	2.52/0.43	ns
		XC6SLX25T	1.52/0.42	1.65/0.42	1.83/0.42	N/A	ns
		XC6SLX45	1.54/0.39	1.59/0.39	1.75/0.39	2.48/0.76	ns
		XC6SLX45T	1.54/0.39	1.59/0.39	1.75/0.39	N/A	ns
		XC6SLX75	1.72/0.41	1.80/0.41	1.99/0.41	2.60/0.75	ns
		XC6SLX75T	1.72/0.41	1.80/0.41	1.99/0.41	N/A	ns
		XC6SLX100	1.34/0.51	1.46/0.51	1.64/0.51	2.12/0.90	ns
		XC6SLX100T	1.34/0.51	1.46/0.51	1.64/0.51	N/A	ns
		XC6SLX150	1.30/0.60	1.40/0.60	1.55/0.60	2.57/0.97	ns
		XC6SLX150T	1.30/0.60	1.40/0.60	1.55/0.60	N/A	ns
		XA6SLX4	1.58/0.37	N/A	1.58/0.37	N/A	ns
		XA6SLX9	1.58/0.37	N/A	1.58/0.37	N/A	ns
		XA6SLX16	2.67/0.35	N/A	2.67/0.17	N/A	ns
		XA6SLX25	1.74/0.27	N/A	1.95/0.27	N/A	ns
		XA6SLX25T	1.74/0.27	N/A	2.03/0.27	N/A	ns
		XA6SLX45	1.58/0.29	N/A	1.87/0.29	N/A	ns
		XA6SLX45T	1.58/0.29	N/A	1.87/0.29	N/A	ns
		XA6SLX75	1.74/0.24	N/A	2.11/0.24	N/A	ns
		XA6SLX75T	1.74/0.24	N/A	2.11/0.24	N/A	ns
		XA6SLX100	N/A	N/A	2.64/0.82	N/A	ns
		XQ6SLX75	N/A	N/A	2.11/0.24	2.60/0.75	ns
		XQ6SLX75T	1.74/0.24	N/A	2.11/0.24	N/A	ns
		XQ6SLX150	N/A	N/A	1.67/0.70	2.57/0.97	ns
		XQ6SLX150T	1.50/0.70	N/A	1.67/0.70	N/A	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include CMT jitter; DCM CLK0 driving PLL, PLL CLKOUT0 driving BUFG.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Source-Synchronous Switching Characteristics

The parameters in this section provide the necessary values for calculating timing budgets for Spartan-6 FPGA source-synchronous transmitter and receiver data-valid windows.

Table 78: Duty Cycle Distortion and Clock-Tree Skew

Symbol	Description	Device ⁽¹⁾	Speed Grade				Units
			-3	-3N	-2	-1L	
T _{DCD_CLK}	Global Clock Tree Duty Cycle Distortion ⁽²⁾	LX4	0.20	N/A	0.20	0.35	ns
		LX9	0.20	0.20	0.20	0.35	ns
		LX16	0.20	0.20	0.20	0.35	ns
		LX25	0.20	0.20	0.20	0.35	ns
		LX25T	0.20	0.20	0.20	N/A	ns
		LX45	0.20	0.20	0.20	0.35	ns
		LX45T	0.20	0.20	0.20	N/A	ns
		LX75	0.20	0.20	0.20	0.35	ns
		LX75T	0.20	0.20	0.20	N/A	ns
		LX100	0.20	0.20	0.20	0.35	ns
		LX100T	0.20	0.20	0.20	N/A	ns
		LX150	0.35	0.35	0.35	0.35	ns
		LX150T	0.35	0.35	0.35	N/A	ns
T _{CKSKEW}	Global Clock Tree Skew ⁽³⁾	LX4	0.25	N/A	0.25	0.29	ns
		LX9	0.25	0.25	0.25	0.29	ns
		LX16	0.15	0.15	0.15	0.22	ns
		LX25	0.26	0.26	0.26	0.41	ns
		LX25T	0.26	0.26	0.26	N/A	ns
		LX45	0.20	0.20	0.20	0.28	ns
		LX45T	0.20	0.20	0.20	N/A	ns
		LX75	0.56	0.56	0.56	0.50	ns
		LX75T	0.56	0.56	0.56	N/A	ns
		XC6SLX100 ⁽⁴⁾	0.22	0.22	0.22	0.21	ns
		XA6SLX100 ⁽⁴⁾	N/A	N/A	0.43	N/A	ns
		LX100T	0.22	0.22	0.22	N/A	ns
		LX150	0.48	0.48	0.48	0.35	ns
		LX150T	0.48	0.48	0.48	N/A	ns
T _{DCD_BUFIO2}	I/O clock tree duty cycle distortion	LX devices	0.25	0.25	0.25	0.50	ns
		LXT devices	0.25	0.25	0.25	N/A	ns

Table 78: Duty Cycle Distortion and Clock-Tree Skew (Cont'd)

Symbol	Description	Device ⁽¹⁾	Speed Grade				Units
			-3	-3N	-2	-1L	
T _{BUFIOSKEW}	I/O clock tree skew across one clock region	LX4	0.06	N/A	0.06	0.07	ns
		LX9	0.06	0.06	0.06	0.07	ns
		LX16	0.06	0.06	0.06	0.07	ns
		LX25	0.06	0.06	0.06	0.07	ns
		LX25T	0.06	0.06	0.06	N/A	ns
		LX45	0.06	0.06	0.06	0.07	ns
		LX45T	0.06	0.06	0.06	N/A	ns
		LX75	0.06	0.06	0.06	0.07	ns
		LX75T	0.06	0.06	0.06	N/A	ns
		LX100	0.06	0.06	0.06	0.07	ns
		LX100T	0.06	0.06	0.06	N/A	ns
		LX150	0.06	0.06	0.06	0.07	ns
		LX150T	0.06	0.06	0.06	N/A	ns

Notes:

1. LXT devices are not available with a -1L speed grade. The LX4 is not available in -3N speed grade.
2. These parameters represent the worst-case duty cycle distortion observable at the pins of the device using LVDS output buffers. For cases where other I/O standards are used, IBIS can be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times.
3. The T_{CKSKEW} value represents the worst-case clock-tree skew observable between sequential I/O elements. Significantly less clock-tree skew exists for I/O registers that are close to each other and fed by the same or adjacent clock-tree branches. Use the Xilinx FPGA Editor and Timing Analyzer tools to evaluate clock skew specific to your application.
4. The T_{CKSKEW} is 0.43 ns for the XA6SLX100 device using a -2 speed grade and 0.22 ns for the XC6SLX100 devices using the -2 speed grade.

Table 79: Package Skew

Symbol	Description	Device	Package ⁽²⁾	Value	Units
T _{PKGSKEW}	Package Skew ⁽¹⁾	LX4	TQG144	N/A	ps
			CPG196	23	ps
			CSG225	58	ps
		LX9	TQG144	N/A	ps
			CPG196	23	ps
			CSG225	58	ps
			FT(G)256	88	ps
			CSG324	64	ps
		LX16	CPG196	19	ps
			CSG225	70	ps
			FT(G)256	71	ps
			CSG324	54	ps
		LX25	FT(G)256	90	ps
			CSG324	61	ps
			FG(G)484	84	ps
		LX25T	CSG324	48	ps
			FG(G)484	112	ps

Table 79: Package Skew (Cont'd)

Symbol	Description	Device	Package ⁽²⁾	Value	Units
T _{PKGSKEW}	Package Skew ⁽¹⁾	LX45	CSG324	70	ps
			CS(G)484	99	ps
			FG(G)484	109	ps
			FG(G)676	138	ps
		LX45T	CSG324	75	ps
			CS(G)484	100	ps
			FG(G)484	95	ps
		LX75	CS(G)484	101	ps
			FG(G)484	107	ps
			FG(G)676	161	ps
		LX75T	CS(G)484	107	ps
			FG(G)484	110	ps
			FG(G)676	134	ps
		LX100	CS(G)484	95	ps
			FG(G)484	155	ps
			FG(G)676	144	ps
		LX100T	CS(G)484	88	ps
			FG(G)484	111	ps
			FG(G)676	147	ps
			FG(G)900	134	ps
		LX150	CS(G)484	84	ps
			FG(G)484	103	ps
			FG(G)676	115	ps
			FG(G)900	121	ps
		LX150T	CS(G)484	83	ps
			FG(G)484	88	ps
			FG(G)676	141	ps
			FG(G)900	120	ps

Notes:

- These values represent the worst-case skew between any two SelectIO resources in the package: shortest delay to longest delay from Pad to Ball.
- Some of the devices are available in both Pb and Pb-free (additional G) packages as standard ordering options. See [DS160: Spartan-6 Family Overview](#) for more information.

Table 80: Sample Window

Symbol	Description	Device ⁽¹⁾	Speed Grade				Units
			-3	-3N	-2	-1L	
T _{SAMP}	Sampling Error at Receiver Pins ⁽²⁾	All	510	510	530	740	ps
T _{SAMP_BUFIO2}	Sampling Error at Receiver Pins using BUFIO2 ⁽³⁾	All	430	430	450	590	ps

Notes:

- LXT devices are not available with a -1L speed grade.
- This parameter indicates the total sampling error of Spartan-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the DCM to capture the DDR input registers' edges of operation. These measurements include:
 - CLK0 DCM jitter
 - DCM accuracy (phase offset)
 - DCM phase shift resolution
These measurements do not include package or clock tree skew.
- This parameter indicates the total sampling error of Spartan-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO2 clock network and IODELAY2 to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

Table 81: Source-Synchronous Pin-to-Pin Setup/Hold and Clock-to-Out Using BUFIO2

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO2							
T _{PSCS} /T _{PHCS}	IFF setup/hold using BUFIO2 clock	XC6SLX4	0.57/0.94	N/A	0.95/1.12	0.27/1.56	ns
		XC6SLX9	0.40/0.95	0.50/0.96	0.60/1.12	0.27/1.56	ns
		XC6SLX16	0.48/0.74	0.55/0.75	0.69/0.83	1.27/1.31	ns
		XC6SLX25	0.28/1.02	0.28/1.12	0.28/1.24	0.15/1.78	ns
		XC6SLX25T	0.28/1.02	0.28/1.12	0.28/1.24	N/A	ns
		XC6SLX45	0.42/1.19	0.44/1.29	0.50/1.40	0.12/1.83	ns
		XC6SLX45T	0.42/1.19	0.44/1.29	0.50/1.40	N/A	ns
		XC6SLX75	0.38/1.48	0.38/1.63	0.38/1.84	0.05/2.78	ns
		XC6SLX75T	0.38/1.48	0.38/1.63	0.38/1.84	N/A	ns
		XC6SLX100	0.06/1.48	0.06/1.63	0.06/1.87	−0.03/2.72	ns
		XC6SLX100T	0.06/1.48	0.06/1.63	0.06/1.87	N/A	ns
		XC6SLX150	0.04/1.73	0.04/1.75	0.04/1.98	−0.08/3.07	ns
		XC6SLX150T	0.04/1.73	0.04/1.75	0.04/1.98	N/A	ns
		XA6SLX4	0.64/0.96	N/A	0.97/1.12	N/A	ns
		XA6SLX9	0.44/0.99	N/A	0.62/1.16	N/A	ns
		XA6SLX16	0.50/0.78	N/A	0.69/0.83	N/A	ns
		XA6SLX25	0.28/1.04	N/A	0.28/1.25	N/A	ns
		XA6SLX25T	0.28/1.04	N/A	0.28/1.25	N/A	ns
		XA6SLX45	0.43/1.21	N/A	0.50/1.40	N/A	ns
		XA6SLX45T	0.43/1.21	N/A	0.50/1.40	N/A	ns
		XA6SLX75	0.38/1.49	N/A	0.38/1.84	N/A	ns
		XA6SLX75T	0.38/1.49	N/A	0.38/1.84	N/A	ns
		XA6SLX100	N/A	N/A	1.01/1.63	N/A	ns
		XQ6SLX75	N/A	N/A	0.38/1.84	0.05/2.78	ns
		XQ6SLX75T	0.38/1.49	N/A	0.38/1.84	N/A	ns
		XQ6SLX150	N/A	N/A	0.04/1.98	−0.08/3.07	ns
		XQ6SLX150T	0.04/1.75	N/A	0.04/1.98	N/A	ns

Revision History

The following table shows the revision history for this document.

Date	Version	Description of Revisions
06/24/09	1.0	Initial Xilinx release.
08/26/09	1.1	Added V_{FS} to Table 1 and Table 2 . Added R_{FUSE} to Table 2 . Added XC6SLX75 and XC6SLX75T to V_{BATT} and I_{BATT} in Table 1 , Table 2 , and Table 4 . Corrected the quiescent supply current for the XC6SLX4 in Table 5 . Updated Table 11 . Removed DV_{PPIN} from Figure 2 . Removed $F_{PCIECORE}$ from Table 24 and added values to $F_{PCIEUSER}$. Added more networking applications to Table 25 . Updated values for $T_{SUSPENDLOW_AWAKE}$, $T_{SUSPEND_ENABLE}$, and T_{SCP_AWAKE} in Table 46 . Numerous changes to Table 47 , page 54 including the addition of new values to various specifications, revising the $T_{SMCKCSO}$ description, and changing the units of T_{POR} . Also, removed <i>Dynamic Reconfiguration Port (DRP) for DCM and PLL Before and After DCLK</i> section from Table 47 and updated all the notes. In Table 52 , added to F_{INMAX} , revised F_{OUTMAX} , and removed PLL Maximum Output Frequency for BUFIO2. Revised values for DCM_DELAY_STEP in Table 54 . Updated CLKIN_FREQ_FX values in Table 55 .
01/04/10	1.2	Added -4 speed grade to entire document. Updated speed specification of -4, -3, -2 speed grades to version 1.03. Added -1L speed grade numbers per speed specification 1.00. Updated T_{SOL} in Table 1 . Added -1L rows for LVCMOS12, LVCMOS15, and LVCMOS18 in Table 9 . Revised much of the detail in GTP Transceiver Specifications in Table 12 through Table 23 . Added -2 data to Table 25 . Updated F_{MAX} in Table 44 . Updated descriptions for T_{DNACKL} and T_{DNACKH} in Table 45 and revised values for all parameters. Removed $T_{INITADDR}$ from Table 47 and added new data. Updated values in Table 48 through Table 62 . Added Table 51 (BUFPLL) and Table 57 (DCM_CLKGEN). Removed $T_{LOCKMAX}$ note from Table 52 . Updated note 3 in Table 53 . In Table 79 : removed XC6SLX75CSG324 and XC6SLX75TCSG324; added XC6SLX75FG(G)484 and XC6SLX75FG(G)484.
02/22/10	1.3	Production release of XC6SLX16 -2 speed grade devices. The changes to Table 26 and Table 27 includes updating this data sheet to the data in ISE v11.5 software with speed specification v1.06. Updated maximum of V_{IN} and V_{TS} and note 2 in Table 1 . In Table 2 , changed V_{IN} , added I_{IN} and note 5, revised notes 1, 6, and 7, and added note 8 to R_{FUSE} . In Table 4 , removed previous note 1 and added data to I_{RPU} , I_{RPD} , and I_{BATT} , changed C_{IN} , added R_{DT} and R_{IN_TERM} , and added note 2 and 3. Updated V_{CCO2} in Table 6 . Added Table 7 and Table 8 . Removed PCI66_3 from Table 9 . Updated PCI33_3 and I2C in Table 9 . Updated the description of Table 11 . Completely updated Table 25 . Updated Table 28 including adding values for PCI33_3. Updated V_{REF} value for HSTL_III_18 in Table 31 . Updates missing V_{REF} values in Table 32 . Added Simultaneously Switching Outputs , page 36 . Removed T_{GSRQ} and T_{RPW} from Table 35 and Table 36 . Also removed T_{DOQ} from Table 36 . Removed T_{ISDO_DO} and note 1 from Table 37 . Removed T_{OSCK_S} and combinatorial section from Table 38 . In Table 39 , removed T_{IODDO_T} and added new tap parameters and note 2. In Table 40 , Table 41 , and Table 42 , made typographical edits and removed notes. Removed clock CLK section in Table 41 . Removed clock CLK section and T_{REG_MUX} and T_{REG_M31} in Table 42 . Added block RAM F_{MAX} values to Table 43 . Updated values and added note 2 to Table 45 . Added values to Table 46 and removed note 1. Numerous changes to Table 47 . Completely updated Table 57 . Revised data in Table 62 . Removed note 3 from Table 71 . Added values to Table 79 . Added data to Table 80 and Table 81 .
03/10/10	1.4	Production release of XC6SLX45 -2 speed grade devices, which includes changes to Table 26 and Table 27 updating this data sheet to the data in ISE v11.5 software with speed specification v1.07. Fixed R_{IN_TERM} description in Table 4 . Added PCI66_3 to Table 7 and replaced note 1. Corrected note 1 and the V, Max for TMDS_33 in Table 8 . In Table 10 , added note 1 to LVPECL_33 and TMDS_33. Also updated specifications for TMDS_33. Updated the GTP Transceiver Specifications section including adding values to Table 16 , Table 17 , and Table 20 through Table 23 . Added PCI66_3 back into Table 9 , Table 28 , Table 31 , Table 32 , and Table 34 . Updated note 3 on Table 32 . In Table 34 , corrected some typographical errors and fixed SSO limits for bank1/3 in FG(G)484 package. Corrected T_{OSCK_OCE} in Table 38 . In Table 57 , updated CLKFX_FREEZE_VAR and CLKFX_FREEZE_TEMP_SLOPE and added typical values to $T_{CENTER_LOW_SPREAD}$ and $T_{CENTER_HIGH_SPREAD}$. Updated and added values to Table 63 through Table 78 , and Table 81 . In Table 79 , revised the XC6SLX16-CSG324 and the XC6SLX45-CSG484 and FG(G)484 values.

Date	Version	Description of Revisions
01/10/11	1.11	Production release of XC6SLX4 and XC6SLX9 in the specific speed grades listed in Table 26 and Table 27 using ISE v12.4 software with speed specification v1.15 for the -4, -3, -3N, and -2 speed grades. Added note 3 to Table 27. Also updated the -1L speed grade requirements to ISE v12.4 software with speed specification v1.06. Revised -3N definition throughout the document. Added note 4 to Table 2 and updated note 5. Added information on V_{CCINT} to note 1 in Table 5. Updated Networking Applications -3 values in Table 25 to match improvements made in ISE v12.4. In Table 28, added note 1 and revised the T_{IOTP} values for LVDS_33, LVDS_25, MINI_LVDS_33, MINI_LVDS_25, RSDS_33, RSDS_25, TMDS_33, PPDS_33, and PPDS_25. Added note 3 to Table 55.
02/11/11	1.12	As described in XCN11008: Product Discontinuation Notice For Spartan-6 LXT -4 Devices, the -4 speed specifications have been discontinued. As outlined in page 2 of the XCN, designers currently using -4 speed specifications should rerun timing analysis using the new -3 speed specifications before moving to a replacement device. Updated the networking applications section of Table 25. Updated -2 speed specifications throughout document and added note 3 to Table 27 advising designers to use the -2 speed specification update (v1.17) with the ISE 12.4 software patch. Added F_{CLKDIV} to Table 37 and Table 38. Updated note 2 in Table 39. Updated units for $T_{SMCKCSO}$ and T_{BPICCO} in Table 47. Updated -1L in Table 71. Removed Note 2: <i>Package delay information is available for these device/package combinations. This information can be used to deskew the package</i> from Table 79.
03/31/11	2.0	Production release of XC6SLX45 in the -1L speed grades listed in Table 26 and Table 27 using ISE v13.1 software with -1L speed specification v1.06. In Table 39, removed values in the -1L column and added note 3 as IODELAY2 only supports Tap0 for lower-power devices. Updated copyright page 1 and Notice of Disclaimer.
05/20/11	2.1	Production release of XC6SLX100 and XC6SLX150 in the specific speed grades listed in Table 26 and Table 27 using ISE v13.1 software with -1L speed specification v1.06. Updated Table 27 and Note 7 with changes per XCN11012: Speed File Change for -3N Devices. Revised Switching Characteristics section for speed specifications: v1.18 for -3, -3N, and -2; including improvements in Table 73 through Table 77 and Table 81. Removed <i>Memory Controller Block</i> from the performance heading in Table 2 and revised Note 2. In Table 4, added Note 1 to C_{IN} and updated the description of R_{IN_TERM}. Updated Note 1 in Table 5. Updated Note 1 of Table 7. In Table 25, added and removed -1L specifications, increased the standard performance DDR3 specifications, removed the extended performance DDR3 row and updated Note 3 and Note 4. Clarified the introductory information for Table 28 and Table 30. In Table 32: Revised V_{MEAS} value for LVCMOS12; revised V_{REF} for LVDS_25, LVDS_33, BLVDS_25, MINI_LVDS_25, MINI_LVDS_33, RSDS_25, and RSDS_33; revised R_{REF} for BLVDS_25 and TMDS_33; and added Note 4 and Note 5. Updated Note 2 and Note 3 in Table 39. In Table 47, revised the values and description of T_{POR} including adding Note 3. Also in Table 47, augmented the description and added specifications for F_{RBCK} and removed XC6SLX4 from F_{MCCK} (maximum frequency, parallel mode (Master SelectMAP/BPI)). Added BUFGMUX to Table 48 title. Added Table 50. In Table 52, revised specifications for $T_{EXTFVAR}$ and $F_{INJITTER}$. In Table 54 removed the 5 MHz < CLKIN_FREQ_DLL parameter in the LOCK_DLL description. In both Table 56 and Table 57, removed the 5 MHz < F_{CLKIN} parameter in the LOCK_FX description. In Table 58, updated description for PSCLK_FREQ and PSCLK_PULSE. Revised title and symbol of Table 70, added new speed specifications for -1L, and added Note 2. Added Table 71.
07/11/11	2.2	Added the Automotive XA Spartan-6 and Defense-grade Spartan-6Q devices to all appropriate tables while sometimes removing the XC6S nomenclature. Added expanded temperature range (Q) to all appropriate tables. Updated T_{SOL} packages in Table 1. Added R_{OUT_TERM} to Table 4. Updated Note 2 on Table 13. Production release of the XC6SLX4, XC6SLX9, XC6SLX16, XC6SLX25, XC6SLX75, XQ6SLX75, and XQ6SLX150 in Table 26 and Table 27 using ISE v13.2 software with -1L speed specification v1.07. Production release of the XA6SLX16, XA6SLX25T, XA6SLX45, XA6SLX45T, XQ6SLX75, XQ6SLX75T, XQ6SLX150, and XQ6SLX150T in Table 26 and Table 27 using ISE v13.2 software with -2 and -3 speed specification v1.19. Added Table 29: IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices(1). Updated CS(G)484 from CSG484 throughout data sheet. Clarified Note 3 in Table 39.
08/08/11	2.3	Production release of the XA6SLX25, XA6SLX75, and XA6SLX75T in Table 26 and Table 27 using ISE v13.2 software with -2 and -3 speed specification v1.19.